

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO.	APPLICATION NO.
	03292.101090.21	10/810,469
	APPLICANT	
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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	CITE NO.	DOCUMENT NUMBER	KIND CODE	DATE	NAME OF PATENTEE OR APPLICANT OF CITED DOCUMENT	PAGES, COLUMNS, LINES WHERE RELEVANT PASSAGES OR RELEVANT FIGURES APPEAR
NN	1	US4443027	A1	4/17/1984	McNeely et al.	
	2	US4450535	A1	5/22/1984	de Pommery et al.	
	3	US4700055	A1	10/13/1987	Kashkashian, Jr, Arsen	
	4	US4736094	A	4/5/1988	Yoshida, Shinya	
	5	US4837422	A	6/6/1989	Dethloff et al.	
	6	US4839504	A	6/13/1989	Nakano, Harumi	
	7	US5016274	A	5/14/1991	Micali et al.	
	8	US5023908	A	6/11/1991	Weiss, Kenneth	
	9	US5025372	A	6/18/1991	Burton et al.	
	10	US5202826	A	4/13/1993	McCarthy, Patrick	
	11	US5276311	A	1/4/1994	Hennige, Hartmut	
	12	US5326964	A	7/5/1994	Risser, J Marlin	
	13	US5350906	A	9/27/1994	D'Hont et al.	
	14	US5365551	A	11/15/1994	Snodgrass et al.	
	15	US5397881	A	3/14/1995	Mannik, Kallis H	
	16	US5453601	A	9/26/1995	D'Hont et al.	
	17	US5461217	A	10/24/1995	Claus, David M	
	18	US5500513	A	3/19/1996	Langhans et al.	
	19	US5504808	A	4/2/1996	Schuermann, Josef	
	20	US5537314	A	7/16/1996	Kanter, Mark W	
	21	US5577120	A	11/19/1996	Penzias, Arno A	
	22	US5578808	A	11/26/1996	Taylor, Douglas C	
	23	US5585787	A	12/17/1996	Wallerstein, Robert S	
	24	US5590038	A	12/31/1996	Pitroda, Satyan G	
	25	US5594227	A	1/14/1997	Deo, Vinay	
	26	US5608778	A	3/4/1997	Partridge, III, B Waring	
	27	US5614703	A	3/25/1997	Martin et al.	
	28	US5641050	A	6/24/1997	Smith et al.	
	29	US5649118	A	7/15/1997	Carlisle, William Reid	
	30	US5689100	A	11/18/1997	Carrithers, David C	
NN	31	US5715399	A	2/3/1998	Bezos, Jeffrey P	

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NN	32	US5724424	A	3/3/1998	Gifford, David K	
	33	US5734838	A	3/31/1998	Robinson et al.	
	34	US5742756	A	4/21/1998	Dillaway et al.	
	35	US5742845	A	4/21/1998	Wagner, Richard Hiers	
	36	US5768385	A	6/16/1998	Simon, Daniel R	
	37	US5770843	A	6/23/1998	Rose, Manning I	
	38	US5778069	A	7/7/1998	Thomlinson, Matthew W	
	39	US5826241	A	10/20/1998	Stein, Lee H	
	40	US5826242	A	10/20/1998	Montulli, Lou	
	41	US5826243	A	10/20/1998	Musmanno et al.	
	42	US5835894	A	11/10/1998	Adcock et al.	
	43	US5852812	A	12/22/1998	Reeder, Mary	
	44	US5858006	A	1/12/1999	Van der AA et al.	
	45	US5859419	A	1/12/1999	Wynn, Sol H	
	46	US5862325	A	1/19/1999	Reed et al.	
	47	US5864306	A	1/26/1999	Dwyer et al.	
	48	US5864830	A	1/26/1999	Armetta et al.	
	49	US5878138	A	3/2/1999	Yacobi, Yacov	
	50	US5878141	A	3/2/1999	Daly et al.	
	51	US5878337	A	3/2/1999	Joao et al.	
	52	US5883810	A	3/16/1999	Franklin et al.	
	53	US5884280	A	3/16/1999	Yoshioka et al.	
	54	US5897622	A	4/27/1999	Blinn et al.	
	55	US5898838	A	4/27/1999	Wagner, Richard Hiers	
	56	US5903875	A	5/11/1999	Kohara, Hiroaki	
	57	US5903880	A	5/11/1999	Biffar, Peter C	
	58	US5905908	A	5/18/1999	Wagner, Richard Hiers	
	59	US5909492	A	6/1/1999	Payne et al.	
	60	US5913203	A	6/15/1999	Wong et al.	
	61	US5914472	A	6/22/1999	Foladare et al.	
NN	62	US5915023	A	6/22/1999	Bernstein, Robert	

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NN	63	US5917168	A	6/29/1999	Nakamura et al.	
	64	US5918216	A	6/29/1999	Miksovsky et al.	
	65	US5923734	A	7/13/1999	Taskett, John M	
	66	US5930767	A	7/27/1999	Reber et al.	
	67	US5930777	A	7/27/1999	Barber, Timothy P	
	68	US5943624	A	8/24/1999	Fox, Thomas M	
	69	US5949044	A	9/7/1999	Walker et al.	
	70	US5949876	A	9/7/1999	Ginter et al.	
	71	US5953710	A	9/14/1999	Fleming, Stephen S	
	72	US5956699	A	9/21/1999	Wong et al.	
	73	US5958004	A	9/28/1999	Helland et al.	
	74	US5960411	A	9/28/1999	Hartman et al.	
	75	US5963915	A	10/5/1999	Kirsch, Steven T	
	76	US5966697	A	10/12/1999	Ferguson et al.	
	77	US5970471	A	10/19/1999	Hill, Charles E	
	78	US5970472	A	10/19/1999	Allsop et al.	
	79	US5970473	A	10/19/1999	Gerszberg et al.	
	80	US5970475	A	10/19/1999	Barnes et al.	
	81	US5979757	A	11/9/1999	Tracy et al.	
	82	US5982293	A	11/9/1999	Everett et al.	
	83	US5983207	A	11/9/1999	Turk et al.	
	84	US5991413	A	11/23/1999	Arditti et al.	
	85	US5991748	A	11/23/1999	Taskett, John M	
	86	US5999914	A	12/7/1999	Blinn et al.	
	87	US6000832	A	12/14/1999	Franklin et al.	
	88	US6009412	A	12/28/1999	Storey, Thomas W	
	89	US6011487	A	1/4/2000	Plocher, Peter H	
	90	US6012039	A	1/4/2000	Hoffman et al.	
	91	US6012143	A	1/4/2000	Tanaka, Hiroshi	
	92	US6012636	A	1/11/2000	Smith, Frank E	
NN	93	US6014634	A	1/11/2000	Scroggie et al.	

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NN	94	US6014635	A	1/11/2000	Harris et al.	
	95	US6014636	A	1/11/2000	Reeder, Kenneth Rodney	
	96	US6014646	A	1/11/2000	Vallee et al.	
	97	US6014648	A	1/11/2000	Brennan, Sherry	
	98	US6014650	A	1/11/2000	Zampese, David	
	99	US6014748	A	1/1/2000	Tushi et al.	
	100	US6016482	A	1/18/2000	Molinari et al.	
	101	US6018718	A	1/25/2000	Walker et al.	
	102	US6021943	A	2/8/2000	Chastain, Robert H	
	103	US6023510	A	2/8/2000	Epstein, Michael A	
	104	US6029147	A	2/22/2000	Horadan et al.	
	105	US6029150	A	2/22/2000	Kravitz, David William	
	106	US6029890	A	2/29/2000	Austin, Frank	
	107	US6029892	A	2/29/2000	Miyake, Susumu	
	108	US6032136	A	2/29/2000	Brake et al.	
	109	US6038292	A	3/14/2000	Thomas, Jerry S	
	110	US6038551	A	3/14/2000	Barlow et al.	
	111	US6041308	A	3/21/2000	Walker et al.	
	112	US6044360	A	3/28/2000	Picciallo, Michael J	
	113	US6058418	A	5/2/2000	Kobata, Hiroshi	
	114	US6061344	A	5/9/2000	Wood, Jr, Clifton W	
	115	US6061789	A	5/9/2000	Hauser et al.	
	116	US6064981	A	5/16/2000	Barni et al.	
	117	US6070150	A	5/30/2000	Remington et al.	
	118	US6070154	A	5/30/2000	Tavor et al.	
	119	US6076078	A	6/13/2000	Camp et al.	
	120	US6078906	A	6/20/2000	Huberman, Bernardo A	
	121	US6078908	A	6/20/2000	Schmitz, Kim	
	122	US6081790	A	6/27/2000	Rosen, Sholom S	
	123	US6088683	A	7/11/2000	Jalili, Reza	
NN	124	US6088717	A	7/11/2000	Reed et al.	

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NN	125	US6088797	A	7/11/2000	Rosen, Sholom S	
	126	US6092198	A	7/18/2000	Lanzy et al.	
	127	US6098053	A	8/1/2000	Slater, Alan	
	128	US6098879	A	8/8/2000	Terranova, Steven N	
	129	US6108641	A	8/22/2000	Kenna et al.	
	130	US6112191	A	8/29/2000	Burke, Bertram V	
	131	US6115458	A	9/5/2000	Taskett, John M	
	132	US6122625	A	9/19/2000	Rosen, Sholom S	
	133	US6125352	A	9/26/2000	Franklin et al.	
	134	US6141752	A	10/31/2000	Dancs et al.	
	135	US6163771	A	12/19/2000	Walker et al.	
	136	US6173269	B1	1/3/2001	Sokol et al.	
	137	US6173272	B1	1/9/2001	Thomas et al.	
	138	US6189787	B1	2/20/2001	Dorf, Robert E	
	139	US6213390	B1	4/10/2001	Oneda, Hideo	
	140	US6220510	B1	4/24/2001	Everett et al.	
	141	US6222914	B1	4/24/2001	McMullin, John L	
	142	US6227447	B1	5/8/2001	Campisano, Kurt M	
	143	US6233683	B1	5/15/2001	Chan et al.	
	144	US6248199	B1	6/19/2001	Smulson, Joel R	
	145	US6263316	B1	7/17/2001	Khan et al.	
	146	US6267292	B1	7/31/2001	Walker et al.	
	147	US6269348	B1	7/31/2001	Pare et al.	
	148	US6293462	B1	9/25/2001	Gangi, Frank J	
	149	US6315195	B1	11/13/2001	Ramachandran, Natarajan	
	150	US6325293	B1	12/4/2001	Moreno, Roland	
	151	US6327573	B1	12/4/2001	Walker et al.	
	152	US6330544	B1	12/11/2001	Walker et al.	
	153	US6336095	B1	1/1/2002	Rosen, Sholom S	
	154	US6353811	B1	3/5/2002	Weissman, Steven I	
NN	155	US6378073	B1	4/23/2002	Davis et al.	

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NN	156	US6402026	B1	6/11/2002	Schwier, Andreas	
	157	US6427910	B1	8/6/2002	Barnes et al.	
	158	US6438235	B2	8/20/2002	Sims, III, J Robert	
	159	US6439455	B1	8/27/2002	Everett et al.	
	160	US6445794	B1	9/3/2002	Shefi, Adam	
	161	US6483427	B1	11/19/2002	Werb, Jay	
	162	US6483477	B1	11/19/2002	Plonka, Robert J.	
	163	US6483929	B1	11/19/2002	Murakami, Rick V	
	164	US6519565	B1	2/11/2003	Clements et al.	
	165	US6520542	B2	2/18/2003	Thompson et al.	
	166	US6587835	B1	7/1/2003	Treyz et al.	
	167	US6598024	B1	7/22/2003	Walker et al.	
	168	US6623039	B2	9/23/2003	Thompson et al.	
	169	US6636833	B1	10/21/2003	Flitcroft et al.	
	170	US6662166	B2	12/9/2003	Pare et al.	
	171	US6669086	B2	12/30/2003	Abdi et al.	
	172	US6671358	B1	12/30/2003	Seidman et al.	
	173	US6681328	B1	1/20/2004	Harris et al.	
	174	US6769718	B1	8/3/2004	Warther et al.	
	175	US6834270	B1	12/21/2004	Pagani et al.	
	176	US6851617	B1	5/8/2005	Saint et al.	
	177	US6853087	B2	2/8/2005	Neuhaus et al.	
	178	US6853894	B1	2/8/2005	Kolls, H Brock	
	179	US6853987	B1	2/8/2005	Cook, David P	
	180	US6857566	B2	2/22/2005	Wankmueller, John	
	181	US6859672	B2	2/22/2005	Roberts et al.	
	182	US6895310	B1	5/17/2005	Kolls, H Brock	
	183	US6994262	B1	2/7/2006	Warther, Richard O	
	184	US7003501	B2	2/21/2006	Ostroff, Maurice	
	185	US7069444	B2	6/27/2006	Lowensohn et al.	
NN	186	US7096204	B1	8/22/2006	Chen et al.	

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NN	187	US7100821	B2	9/5/2006	Rasti, Mehran Randall	
	188	US7103575	B1	9/5/2006	Linehan, Mark Holmes	
	189	US7136835	B1	11/14/2006	Flitcroft et al.	
	190	US7213748	B2	5/8/2007	Tsuei et al.	
	191	USRE37822	E	8/27/2002	Anthonyson, Robert B	
	192	US20010034565	A1	10/25/2001	Leatherman, Russel Dean	
	193	US20010034720	A1	10/25/2001	Armes, David	
	194	US20010049628	A1	12/6/2001	Icho, Robert	
	195	US20020026419	A1	2/28/2002	Maritzen, et al	
	196	US20020028704	A1	3/7/2002	Bloomfield, et al	
	197	US20020046341	A1	4/18/2002	Kazaks, et al	
	198	US20020052839	A1	5/2/2002	Takatori, Sunao	
	199	US20020074398	A1	6/20/2002	Lancos, et al	
	200	US20020077895	A1	6/20/2002	Howell, Steve	
	201	US20020095298	A1	7/18/2002	Ewing, Christopher	
	202	US20020095343	A1	7/18/2002	Barton, et al	
	203	US20020111917	A1	8/15/2002	Hoffman, et al	
	204	US20020154795	A1	10/24/2002	Lee, et al	
	205	US20020174067	A1	11/21/2002	Hoffman, et al	
	206	US20030018567	A1	1/23/2003	Flitcroft, et al	
	207	US20030028481	A1	2/6/2003	Flitcroft, et al	
	208	US20030054836	A1	3/20/2003	Michot, Gerard	
	209	US20030055727	A1	3/20/2003	Walker, et al	
	210	US20030130820	A1	7/10/2003	Lane, III, George H	
	211	US20030195037	A1	10/16/2003	Vuong, et al	
	212	US20040006539	A1	1/8/2004	Royer, et al	
	213	US20040016796	A1	1/29/2004	Hann, et al	
	214	US20040020982	A1	2/5/2004	Hoffman, et al	
	215	US20040039814	A1	2/26/2004	Crabtree, et al	
	216	US20040044627	A1	3/4/2004	Russell, et al	
NN	217	US20040083184	A1	4/29/2004	Tsuei, et al	

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NN	218	US20050038718	A1	2/17/2005	Barnes, et al	
↓	219	US20050040272	A1	2/24/2005	Argumedo, et al	
↓	220	US20050119978	A1	6/2/2005	Ates, Fikret	
NN	221	US20050121512	A1	6/9/2005	Wankmueller, John	

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NN	1	0 484 726	EP	A1	5/13/1992	Andersson, Thorbjorn	
↓	2	1 115 095	EP	A2	7/11/2001	Flitcroft, et al	
↓	3	2 361 790	UK	A	10/31/2001	Arndt, et al	
↓	4	00/049586	WO	A1	8/24/2000	Flitcroft, et al	
↓	5	97/009688	WO	A3	3/13/1997	Simon, Daniel R	
NN	6	99/049424	WO	A1	9/30/1999	Flitcroft, et al	

NON-PATENT LITERATURE DOCUMENTS

EXAMINER INITIAL	CITE NO.	
NN	1	"Credit Card Offer Travelers New Benefit", PR Newswire, 08/05/1987
↓	2	"Fingerprint Analysis- The Basics", http://www.crimtrac.gov.au/fingerprintanalysis.htm , 02/18/2004, 3 pages
↓	3	"Fingerprint Technology- Identix Inc.- Empowering Identification™- Understanding Biometrics", http://www.identix.com/newsroom/news_biometrics_finger.html , 02/18/2004, 1 page
↓	4	"Identix Inc. - Empowering Identification™ - Understanding Biometrics", http://www.identix.com/newsroom/news_biometrics_face.html , 1 page
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FORM PTO 449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. 03292.101090.21	APPLICATION NO. 10/810,469
	APPLICANT David S. Bonalle et al.	
	FILING DATE March 27, 2004	GROUP 2612

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